

Cryogenic cathodoluminescence of $\text{Cu}_x\text{Ag}_{1-x}\text{InSe}_2$ thin films

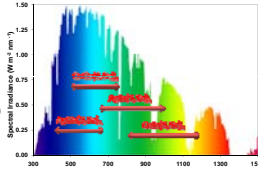
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Motivation

- $\text{Cu}(\text{In,Ga})\text{Se}_2$ is leading choice for high performance thin film solar cells (20.1% efficiency)
- Bandgaps of the I-III-VI₂ system (I-Cu,Ag; III-Ga,In; VI-S,Se) cover almost the entire solar spectrum, which make it an ideal system for multijunction solar cells
- However, these make poor solar cells because most of their properties, including recombination mechanisms, are poorly understood
- Cathodoluminescence (CL) offers simultaneous scanning of electron and spectroscopic images
- Our goals are to:
 - Study luminescence behavior close to grain boundaries
 - Identify emission differences between samples (Cu vs Ag)
 - Characterize emissions and possible defects responsible for transitions
- First report of cryogenic CL with spectral imaging on AgInSe_2 and $\text{Cu}_x\text{Ag}_{1-x}\text{InSe}_2$

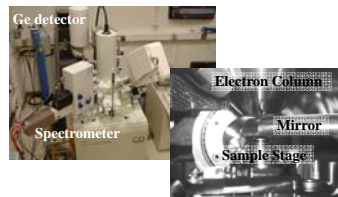


Experimental Setup

Thin film deposition system

- Hybrid sputtering/evaporation
 - Sputtering of metals (Cu, Ag, In)
- Substrate held at 550°C
- Three films analyzed
 - AgInSe_2 – 300 nm
 - $\text{Cu}_{0.6}\text{Ag}_{0.4}\text{InSe}_2$ – 700 nm
 - CuInSe_2 – 700 nm

JEOL 7000F analytical SEM



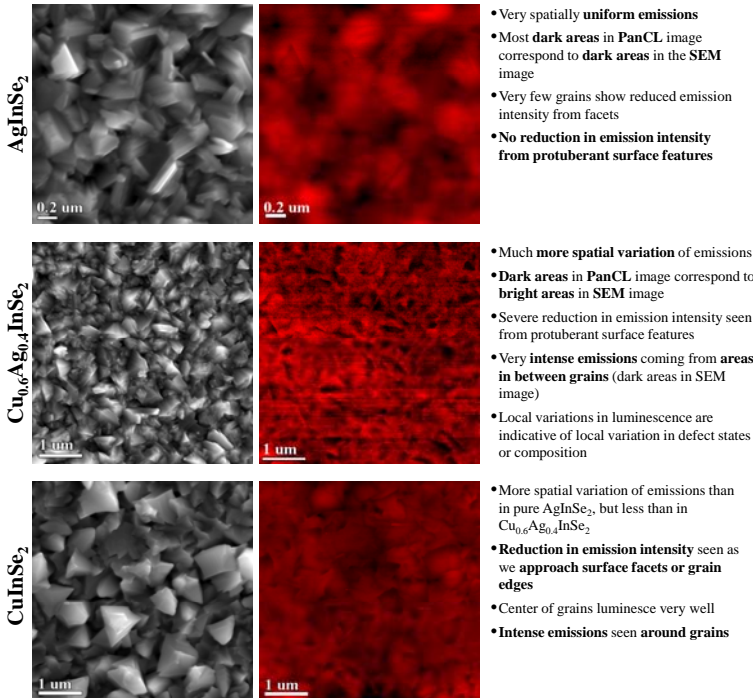
- Gatan MonoCL3 Spectrometer
- Liquid N₂-cooled Ge detector
- Liquid He-cooled stage module
- Sample temperature ~ 5K
- Accelerating Voltage = 15 kV
- Current varied from 22 pA-160,000 pA
- Some samples were carbon coated to avoid charging during imaging

Panchromatic CL Imaging

SEM Images

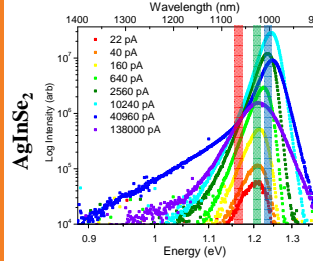
PanCL Images

Observations



Power-series and Spectral Imaging

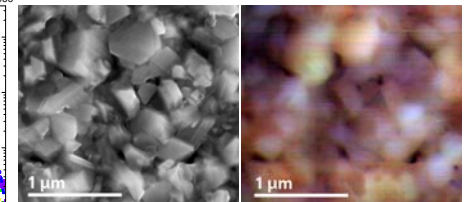
Power-dependent Spectra



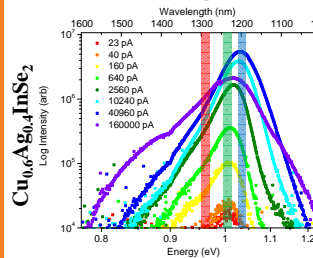
- Single Gaussian + exponential tail at low excitation power
- At excitation powers above 2560 pA we see new exponential tails at both the high and low energy ends
- Blue shift of main Gaussian peak

SEM Images

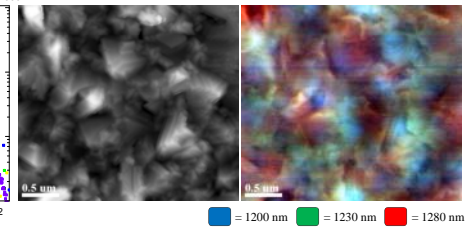
Monochromatic CL Overlay



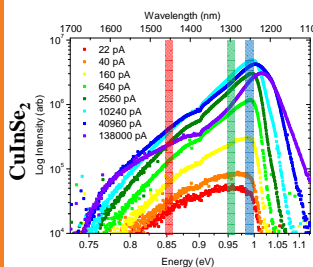
- Aligned and overlaid spectral images show **spatial and spectral uniformity**
- No enhanced emission from grain boundaries or inter-grain areas
- **Uniformity in emission indicates compositional uniformity**



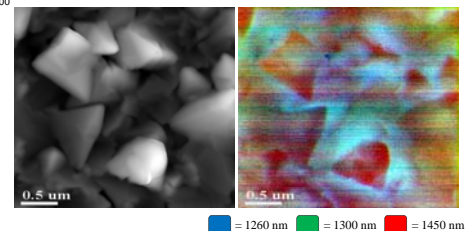
- Two Gaussians at low excitation power
- Low and high energy end exponential tails appear at higher excitation powers together with additional Gaussian
- Blue shift of Gaussian peaks



- Aligned and overlaid spectral images show **spatial and spectral variation**
- Enhanced emission from grain boundaries and inter-grain areas
- **CAIS has the most variation of emissions from grain to grain, indicating compositional fluctuations between grains**



- Very broad emission requires 4+ peaks to fit + exponential tail at low energy
- High energy (1200 nm) Gaussian starts emitting above 640 pA
- Blue shift of main Gaussian peaks



- Aligned and overlaid spectral images show **spatial and spectral variation**
- Red emission, although very uniform, is most intense inside grains even close to facets and surface features
- Green and blue emissions strongest from grain boundaries and inter-grain areas
- **CIS has most emission variation from grain to boundary indicating compositional fluctuation between grain and grain boundaries**

Conclusions

- Emissions from AgInSe_2 are **more uniform** both spatially and spectrally than Cu-containing samples
- AgInSe_2 less affected by reduced emission from surface features – partly due to less surface faceting
- **Cu-containing samples exhibit enhanced luminescence from grain boundary or inter-grain areas**
- Both **Cu-containing samples exhibit localized luminescent variations** indicative of **compositional fluctuations or electrically active defect fluctuations**
- As **Cu increases, emission gets broader** indicating larger number of specific defect states (more local chemical variation)
- **Device implications:** AIS may produce **more uniform cell performance** and may exhibit **less air-sensitivity** during manufacture

Acknowledgments

- This work was carried out in part in the Frederick Seitz Materials Research Laboratory Central Facilities, University of Illinois, which are partially supported by the U.S. Department of Energy under grants DE-FG02-07ER46453 and DE-FG02-07ER46471
- Toledo acknowledgements: Ohio Department of Development (ODOD), Wright Center for Photovoltaics Innovation and Commercialization (PVIC)
- This work was supported by Air Force Research Laboratory, Space Vehicles Directorate, Kirtland AFB (Contract No. FA9453-08-C-0172)
- Special thanks to: Dr. James Mabon (SEM/CL setup) and co-workers Allen Hall, Damon Hebert, Pamela Martin, and Yiming Liu